

<b>Notice of References Cited</b>	Application/Control No. 10/511,525	Applicant(s)/Patent Under Reexamination CHANG ET AL.	
	Examiner Rita J. Desai	Art Unit 1625	Page 1 of 1

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*	B	US-6,110,914	08-2000	Phillips et al.	514/233.2
*	C	US-6,569,865	05-2003	Eifion, Phillips	514/278
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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